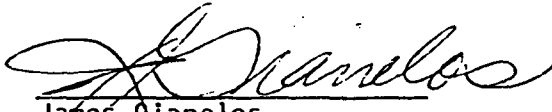


B.F. GOODRICH COMPANY TECHNICAL REPORT

25-1612

Title XRF Measurement of TBTO Trapped on Two Filter Paper Stacks		
Author J. Giannelos	Location Brecksville R & D Center, D/8510	Date Sept. 3, 1976
To: <u>O. S. Kurtz</u> P. M. Zakriski	Location Brecksville R & D Center, D/8506	Project No. 8504
Summary X-ray fluorescence (XRF) was easily able to measure the tin from the TBTO (tributyl-tin oxide) which you trapped on two stacks of filter papers, which had been connected in series (one stack after the other). The first stack of filter papers had a tin L_α count rate of 3,000 counts/second (c/s) while the second stack had a count rate of about 80 c/s. This means that about 97% of the tin measured was trapped on the first filter stack, and that this method of trapping is a feasible way of determining whether the TBTO-like odors which drift into your laboratory are TBTO or not. A copy of the XRF scans is attached.  James Giannelos jb		
Log Book Reference: 3407		
Distribution: R & D Files C. H. Lufter		

BFG-I- 507

